Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/543,190	TATEMATSU ET AL.		
Examiner	Art Unit		
Huan H. Tran	2861		

	SFAR	CHED	
	JEAN		
Class	Subclass	Date	Examiner
347	212,155 156	1/4/2007	ннт
399	320,322	1/4/2007	ннт
399	323	1/4/2007	ннт
updated		4/26/2007	ннт
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INTERFERENCE SEARCHED			
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SEARCH N (INCLUDING SEARC		·)
	DATE	EXMR
(347/212,155,156 or 399/320,322,323).ccls.	1/4/2007	ннт
g03g015/20.ipc.	1/4/2007	ннт